Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/749,437	CHANG ET AL.	
Examiner	Art Unit	
Brian S. Kwon	1614	

SEARCHED				
Class	Subclass	Date	Examiner	
514	266.4	7/30/2006	вк I	
	255.4			
	253.01			
	282	1/		
	252.13	V	V	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
STN (REG, CAPLUS, BIOSIS, EMBASE, USPAT)	7/30/2006	вк
EAST, NPL		
Continuity Data, Inventor Name Search		